

**Search Notes**

Application/Control No.

10/606,487

Examiner

Anthony Fick

Applicant(s)/Patent under  
Reexamination

GEE ET AL.

Art Unit

1753

**SEARCHED**

Class	Subclass	Date	Examiner
136	252, 256	9/12/2006	ADF

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
136	252, 256	9/12/2006	ADF

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See EAST search history	9/12/2006	ADF
Inventor search	9/7/2006	ADF
Consulted with Jeffrey Barton and Nam Nguyen	9/11/2006	ADF
Internet database search, IEEE and Google scholar, for inventors and keywords	9/8/2006	ADF